

# INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

FIS9-2001-02 US1

Application Number

10/035061

Applicant(s)

AUSSCHNITT ET AL.

Filing Date

12-28-2001

Group Art Unit

2877

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
M		5,805,290	09-08-98	AUSSCHNITT ET AL.			
M		6,091,486	07-18-00	KIRK			
ES		5,300,786	04-05-94	BRUNNER ET AL.			

35714 U.S. PRO  
10/035061  
12/28/01

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

* N		<del>SPIE 3597 - "Application of blazed gratings for determination of equivalent primary azimuthal aberrations" Kirk and Proglor</del>
		<del>'SPIE 4000 - "Impact of high order aberrations on the performance of the aberration monitor" - Dirksen et al.</del>
		<del>SPIE 4000 - "In situ measurement of lens aberrations" Farrar et al.</del>

EXAMINER

Michael Stahl

DATE CONSIDERED

2-25-04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\* The following were not considered since they failed to provide a date of publication.